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	STATEMENT	BY APPL		S 4 3007	Filing Date	04/26/2001	RECEIVED
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U.S. PATENT DOCUMENTS									
Examiner initials*	Cite No.1	U.S. Patent	Document		Date of Publication of	Pages, Columns, Lines,			
		Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear			
FER	A1	5,774,664		Jack D. Hidary et al.	06/30/1998	· · · · · · · · · · · · · · · · · · ·			
FFH	A2	5,982,445		Mark K. Eyer et al.	11/09/1999				
FFIX	A3	5,987,509		Michael J. Portuesi	11/16/1999				
te 1+	A4	6,058,430		Kenneth B. Kaplan	05/02/2000				
CEN	A5	5,929,849		Dan Kikinis	07/27/1999				

					F	DREIGN PATENT DOCUMENT	rs		
Examiner Initials*	Cite No. ¹	Foreign Patent Document Office ³ Number ⁴ Kind Code ⁵ (if known)			ode ⁵	Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Т ⁶
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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	-				
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s publisher, city and/or country where published.					
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			79.406%. PA	ATEN	T DOCUMENTS				
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUB- CLASS	FILING II APPRO	=
FEU	A1	6,199,206 B1	03/06/2001	Nish	ioka et al.	725	51	10/23	/1996
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Sheet 1 of 1 U.S. DEPARTMENT OF COMMERCE Form PTO-1449 ATTY, DOCKET NO. SERIAL NO. 041892-0210 09/843,397 PATENT AND TRADEMARK OFFICE (MODIFIED) APPLICANT **SUPPLEMENTAL** NEORMATION DISCLOSURE CITATION Martin Pearson, et al. **FILING DATE GROUP ART UNIT** April 26, 2001 se several sheets if necessary) Unassigned **U.S. PATENT DOCUMENTS FILING DATE DOCUMENT** SUB-DATE **CLASS** REF NAME IF INITIAL CLASS **NUMBER APPROPRIATE** 4,847,698 07/11/1989 Freeman 358 343 07/16/1987 07/16/1987 4,847,700 07/11/1989 358 343 Freeman 12/17/1996 348 485 08/12/1994 Harper et al. 5.585.858 03/31/1998 348 . 12 11/30/1993 5,734,413 Lappington et al. 12 06/07/1995 5,764,275 06/09/1998 Lappington et al. 348 01/19/1999 Freeman et al. 345 302 02/08/1996 5,861,881 5,872,588 02/16/1999 Aras et al. 348 1 12/06/1995 03/16/1999 Herz et al. 348 465 07/09/1996 5,883,675 455 07/01/1996 08/10/1999 Kalluri et al. 6.1 5,937,331 218 12/20/1996 11/23/1999 Yen et al. 709 5,991,799 709 217 03/11/1996 12/21/1999 Zdepski et al. 6,006,256 09/09/1996 6,058,430 05/02/2000 Kaplan 709 245 348 478 01/08/1998 05/16/2000 Born et al. 6,064,440 05/08/1997 06/13/2000 Matsuura 348 478 6,075,568 463 40 09/29/1997 02/27/2001 **Junkin** 6,193,610 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT SUB-CLASS DATE COUNTRY **REF** NUMBER CLASS YES NO OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED **EXAMINER** EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next

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